

P603 / P750 set

RF Conducted Measurement Analysis, 1 Ohm / 150 Ohm



Short description

The probe set is used to measure conducted emissions (measurements with direct 1 Ohm/150 Ohm-coupling) at IC pins. For the current and voltage measurement there is one respective probe available. Every Test-IC pin can be reached and contacted by the probe.

The measurements with the probe set guarantee a high precision when repeated and comparability of measurements.

The ICE1 IC test environment of Langer EMV-Technik is used to start the test IC. measurements can be done with ChipScan-ESA software. Measurement results of all measured pins are saved in the software and can be compared fast and systematically.

Scope of delivery

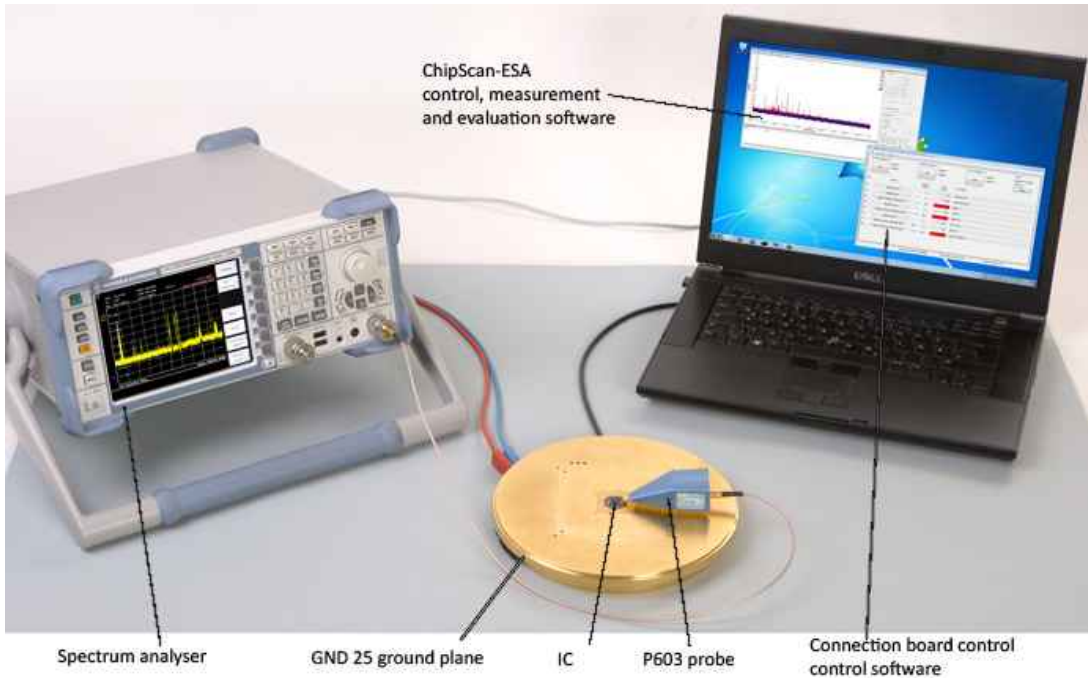
- 1x P603, RF Current Probe 1 Ohm
- 1x P750, RF Voltage Probe 150 Ohm
- 1x CS-ESA, ChipScan-ESA Software / USB
- 1x SMA-SMB 1 m, SMA-SMB Measuring Cable
- 1x P603 / P750 case, System Case
- 1x P603 / P750 m, P603 / P750 Set User Manual

P603 / P750 set

RF Conducted Measurement Analysis, 1 Ohm / 150 Ohm



Application with P603



Scheme measurement set-up with P750

